

Docket No.: K0600.0215/P215
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Kenzo Hiraoka

Allowed: August 11, 2008

Application No.: 10/594,837

Confirmation No.: 3719

Filed: September 28, 2006

Art Unit: 2881

For: IONIZATION METHOD AND
APPARATUS FOR MASS ANALYSIS

Examiner: M.P. Maskell

COMMENTS ON STATEMENT OF REASONS
FOR ALLOWANCE UNDER 37 CFR §1.104(e)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

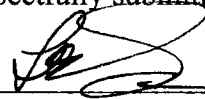
While Applicant agrees in part with the Examiner's stated reasons for allowance, in that the prior art does not anticipate, or render obvious, the claimed invention, Applicant notes that the reasons for allowance fails to address all limitations of all of the allowed claims. For example, certain claim limitations were not discussed in the Examiner's Reasons for Allowance, including those in the dependent claims, each of which defines a unique combination of features not shown or suggested by the prior art.

The stated reasons for allowance should be interpreted as highlighting only some of the reasons why the claims are allowable. The scope of the claims should be interpreted based on the actual language of the allowed claims and limitations should not be inferred from the Examiner's Statement of Reasons for Allowance.

Dated: November 10, 2008

Respectfully submitted,

By



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